

F1: Silicon 3D-Integration Technology and Systems

Organizer:	Pascal Urard , <i>STMicroelectronics, Crolles, France</i>
Co-organizer:	Ken Takeuchi , <i>University of Tokyo, Tokyo, Japan</i>
Chair:	Kerry Bernstein , <i>Applied Research Associates, South Royalton, VT</i>
Committee:	Hideto Hidaka , <i>Renesas Technology, Itami, Japan</i> Michael Phan , <i>Qualcomm, Raleigh, NC</i> Joo Sun Choi , <i>Samsung Electronics, Hwasung, Korea</i> Bob Payne , <i>Texas Instruments, Dallas, TX</i> Vladimir Stojanovic , <i>MIT, Cambridge, MA</i> Kees Van Berkel , <i>ST-Ericsson, Eindhoven, The Netherlands</i> Takayasu Sakurai , <i>University of Tokyo, Tokyo, Japan</i>

This Forum brings together 3D-integration technologies (System-in-Package, Through-Silicon-Via, Contactless-Chip-to-Chip-Communication,...), key components (SDRAM, flash, SoC, sensor,...) and 3D applications (imagers, smart phones, solid-state disk drives,...).

Key issues addressed by the panel experts will include:

- 3D-integration standards
- 3D-integration technologies: SiP, Chip-Scale Packages, Bit-Cost-Scalable 3D cell stacking, TSV, contactless interfaces,...
- Power issues, mechanical issues, temperature distribution
- Product benefits and yields

And, finally, the panel will provide an answer to the question: When will 3D be ready for show time?

Forum Agenda

<u>Time</u>	<u>Topic</u>
8:00	Breakfast
8:20	Introduction Pascal Urard , <i>STMicroelectronics, Crolles, France</i>
8:30	3D TSVs - Ready for Design! Pol Marchal , <i>IMEC, Leuven, Belgium</i>
9:15	3D for Wireless Mobile Multimedia Applications - Opportunities and Challenges Georg Kimmich , <i>ST-Ericsson, Grenoble, France</i>
10:00	Break
10:15	Chip-Scale Camera Module Using Through-Silicon-Via Jean-Luc Jaffard , <i>STMicroelectronics, Grenoble, France</i>
11:00	2.5D & 3D ICs: Solutions & Challenges Ho-Ming Tong , <i>ASE Group, Kaoshiung, Taiwan</i>
11:45	Contactless Interfaces in 3D-Integration Hiroki Ishikuro , <i>Keio University, Yokohama, Japan</i>
12:30	Lunch
1:30	Advancements in SiP Integration and Interconnect Technology Flynn Carson , <i>STATS ChipPACK, Singapore</i>
2:15	TSV Technology and its Application to DRAM Uksung Kang , <i>Samsung, Korea</i>
3:00	Break
3:15	3D Flash Memory Technology and Circuit Design Yoshihisa Iwata , <i>Toshiba, Yokohama, Japan</i>
4:00	3D Integration Challenges in Computing Samuel Naffziger , <i>AMD, Fort Collins, CO</i>
4:10	Panel Discussion
5:10	Conclusion
